



PATENT
1152-0263P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Hideaki SAKAGUCHI Conf.: 4601
Appl. No.: 09/624,014 Group: 2857
Filed: July 21, 2000 Examiner: Mary C. BARAN
For: TESTING DEVICE & TESTING METHOD FOR
SEMICONDUCTOR INTEGRATED CIRCUITS

COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

May 12, 2004

Sir:

The Examiner's statement of reasons for allowance appears to present an accurate summary of features not shown in the prior art of record. However, Applicant notes that it is the claims themselves that define the scope of the invention for which protection is sought.

Respectfully submitted,

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By


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